

## Technical Program for TestForum 2026 (preliminary rev. 0.1)

**Tuesday, December 1<sup>st</sup>, 2026**

| Time               | Titles                                                                                                      | Speakers or additional info                      |
|--------------------|-------------------------------------------------------------------------------------------------------------|--------------------------------------------------|
| 08:15-08:30        | Registration                                                                                                |                                                  |
| <b>08:30-08:40</b> | <b>Welcome / Introduction</b>                                                                               | Knut Båstøløkken                                 |
| <b>08:40-09:40</b> | <b>Key Note Session</b>                                                                                     | <i>Chairman: Knut Båstøløkken</i>                |
| 08:40-09:40        | How cybersecurity and the CRA will change your job as a test engineer                                       | Steve Summers, Emerson Test and Measurement (NI) |
| <b>09:40-10:20</b> | <b>Exhibitor Forum: short presentations</b>                                                                 | <i>Chairman: Artur Jutman</i>                    |
| 10:20-11:00        | Coffee Break / Exhibition                                                                                   |                                                  |
| <b>11:00-12:30</b> | <b>Session 1: Structural test 1 / Battery test</b>                                                          | <i>Chairman: Mika Pussinen</i>                   |
| 11:00-11:30        | 1.1 The Evolution of Testing: How AI empowers Test Program Generation                                       | Lothar Diez, SPEA                                |
| 11:30-12:00        | 1.2 ULTRA technology: a must to meet hyperscalers test needs                                                | Andrea Romano, Seica                             |
| 12:00-12:30        | 1.3 INGUN - Partner for Future Technology                                                                   | Christian Knauf / Ralf Schmid, Ingun             |
| 12:30-13:30        | Lunch                                                                                                       |                                                  |
| <b>13:30-15:00</b> | <b>Session 2: Structural test 2 / Test Automation</b>                                                       | <i>Chairman: Paulius Musteikis</i>               |
| 13:30-14:00        | 2.1 Faster inspection with deeper insight & Intelligent verification station                                | Chanderkant Vaid, GÖPEL electronic GmbH          |
| 14:00-14:30        | 2.2 Next level thermal imaging for detecting open ends for non-destructive validation testing               | Dirk Faber, CN Rood                              |
| 14:30-15:00        | 2.3 The Next Test Bottleneck: Scaling Electronics Production Without Scaling Labor                          | Dragos-Andrei Beldiman, Brooks                   |
| 15:00-15:40        | Coffee Break / Exhibition                                                                                   |                                                  |
| <b>15:40-17:10</b> | <b>Session 3: IJTAG / Security</b>                                                                          | <i>Chairman: Raimedas Sodaitis</i>               |
| 15:40-16:10        | 3.1 IJTAG in Practice: Where Interoperability Still Breaks, and What Is Being Done About It                 | Reginald Waller, Asset Intertech                 |
| 16:10-16:40        | 3.2 Security issues with JTAG/IJTAG                                                                         | Erik Larsson, Lund University                    |
| 16:40-17:10        | 3.3 The evolution of CAD formats in the electronics industry                                                | Hermann Reischer, Polar Instruments GmbH         |
| 17:10-17:40        | Fruit & Refreshments / Exhibition                                                                           |                                                  |
| <b>17:40-19:00</b> | <b>Panel debate:</b>                                                                                        | <i>Panel moderator: Birger Schneider</i>         |
|                    | <b><i>Cybersecurity, Cyber Resilience Act (CRA) and Other Security Issues in Testing of Electronics</i></b> |                                                  |
| <b>19:30</b>       | <b>Gala Dinner</b>                                                                                          |                                                  |

**Wednesday, December 2<sup>nd</sup>, 2026**

| Time               | Titles                                                                                                  | Speakers or additional info                      |
|--------------------|---------------------------------------------------------------------------------------------------------|--------------------------------------------------|
| <b>08:30-10:00</b> | <b>Session 4: Test data analysis</b>                                                                    | <i>Chairman: Erik Larsson</i>                    |
| 08:30-09:00        | 4.1 Test data analysis with WATS Alvea and MCP                                                          | Natanya Sukkot, Virinco                          |
| 09:00-09:30        | 4.2 Finding the Signal in the Noise: Hidden Insights from Manufacturing Test Data                       | Yee Shuen Hung, Keysight Technologies            |
| 09:30-10:00        | 4.3 PCB Repair and Rework with AI That Knows the Board and Its History                                  | Giorgio Insinga, ARBoard                         |
| 10:00-10:45        | Coffee Break / Exhibition                                                                               |                                                  |
| <b>10:45-12:15</b> | <b>Session 5: JTAG based test / RF test</b>                                                             | <i>Chairman: Mattias Ericsson</i>                |
| 10:45-11:15        |                                                                                                         | Jan Heiber, Göpel electronic                     |
| 11:15-11:45        |                                                                                                         | Anthony Sparks, JTAG Technologies                |
| 11:45-12:15        | 5.3 From Model to RF: Practical Prototyping and Validation for Next-Generation Wireless Systems         | Aku Wilenius, CN Rood                            |
| 12:15-13:30        | Lunch                                                                                                   |                                                  |
| <b>13:30-15:00</b> | <b>Session 6: AI</b>                                                                                    | <i>Chairman: Mats Klarholm</i>                   |
| 13:30-14:00        | 6.1 Why AI is Becoming Essential in Test—and How Nigel Enables It                                       | Steve Summers, Emerson Test and Measurement (NI) |
| 14:00-14:30        | 6.2 (AI integrated in test)                                                                             | Teit Poulsen, Altoo                              |
| 14:30-14:45        | Short break                                                                                             |                                                  |
| 14:45-15:45        | <b>Session 7: Functional test / Test strategies</b>                                                     | <i>Chairman: Harri Korhonen</i>                  |
| 14:45-15:15        | 7.1 AI engineered functional test: agent-controlled instrumentation with MCP interface                  | Artur Jutman, Testonica                          |
| 15:15-15:45        | 7.2 From DFT to Production Confidence: Practical Strategies for Modular, High-Coverage Electronics Test | Vojtech Camfrla, UNITES Systems a.s.             |
| 15:45-16:00        | Closing Session: TestForum concluding remarks                                                           | <i>Knut Båttstøløyken, Kitron</i>                |